Introduction
NASA spacecraft are subject to a harsh space environment that includes exposure to various types of ionizing radiation. This exposure can cause single event effects (SEE), which can have serious consequences for spacecraft design. In this work, we present a study of SEE effects on spacecraft components, specifically focusing on the single event transient (SET) LET threshold. We present experimental results on a variety of commercial devices, including linear and mixed signal devices, as well as power devices.

Test Techniques and Setup
A. Test Facilities

B. Test Methods

Test Results Overview

Test Results and Discussion

Table: Summary of SEE Test Results

Summary

References